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Bib Data Sheet

CONFIRMATION NO. 3769

SERIAL NUMBER 10/648,231	FILING DATE 08/27/2003  RULE	CLASS 716	GROUP ART UNIT 2825	ATTORNEY DOCKET NO. 520.43079X00
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\*\* CONTINUING DATA \*\*\*\*\*

None TT

\*\* FOREIGN APPLICATIONS \*\*\*\*\*

Verified TT

JAPAN 2003-033522 02/12/2003 NO

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

\*\* 11/28/2003

Foreign Priority claimed

☒ yes ☐ no35 USC 119 (a-d) conditions  
met☒ yes ☐ no ☐ Met after  
AllowanceVerified and  
Acknowledged*Tanaka T*  
Examiner's SignatureTT  
Initials

STATE OR

COUNTRY  
JAPAN

SHEETS

DRAWING  
18

TOTAL

CLAIMS  
18

INDEPENDENT

CLAIMS  
6

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## TITLE

System and method for evaluating a semiconductor device pattern, method for controlling process of forming a semiconductor device pattern and method for monitoring a semiconductor device manufacturing process

FILING FEE

RECEIVED  
1132

FEES: Authority has been given in Paper  
No. \_\_\_\_\_ to charge/credit DEPOSIT ACCOUNT  
No. \_\_\_\_\_ for following:

☐ All Fees☐ 1.16 Fees ( Filing )☐ 1.17 Fees ( Processing Ext. of  
time )☐ 1.18 Fees ( Issue )